Form PTO-1449

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ATTY. DOCKET NO.	APPLICATION NO.
4035-0165P	10/796,990
APPLICANT: MIURA, Yasuyuki et al.	
FILING DATE: March 11, 2004	GROUP: ~~UNASSIGNED~~ 2609

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	Kind	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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/WK/	DALLY et al., "Deadlock-Free Adaptive Routing in Multicomputer Networks Using Virtual Channels," IEEE Transactions on Parallel and Distributed Systems, Vol. 4, No. 4, April 1993, pp. 466-475.
/WK/	DUATO, "A New Theory of Deadlock-Free Adaptive Routing in Wormhole Networks," IEE Transactions on Parallel and Distributed Systems, Vol. 4, No. 12, December 1993, pp. 1320-1331.
/WK/	YANG et al., "Adaptive Routing in *k*-ary *n*-cube Multicomputers," Proc. Of ICPADS, 1996, pp. 404-411
/WK/	JAIN et al., "TESH: A New Hierarchical Interconnection Network for Massively Parallel Computing," IEICE Trans. Inf. & Syst., Vol. E80-D, No. 9, September 1997, pp. 837-845.
/WK/	HORIGUCHI, "Wafer Scale Integration," Proceedings of the 6th International Microelectronics Conference," May 30-June 1, 1990, Tokyo Japan, pp. 51-58.
/WK/	LITTLE et al., "The 3-D Computer," IEEE International Conference on Wafer Scale Integration, 1989, pp. 55-64.
/WK/	CAMPBELL et al., "3-D Wafer Stack Neurocomputing," IEEE International Conference on Wafer Scale Integration, 1993, pp. 67-74.
/WK/	CARSON, "The Emergence of Stacked 3D Silicon and its Impact on Microelectronics Systems Integration," IEEE Innovative Systems in Silicon, 1996, pp. 1-8.
/WK/	KURINO et al., "Three-Dimensional Integration Technology for Real Time Micro-Vision System," IEEE International Conference on Innovative Systems in Silicon, 1997, pp. 203-212.

EXAMINER	DATE CONSIDERED
/Wei Po Kao/ (09/02/2007)	

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